

XRF

PRACTICAL X-RAY FLUORESCENCE COURSE

20-24 April 2026

Techniques & Skills to Maximize Results!



LECTURES

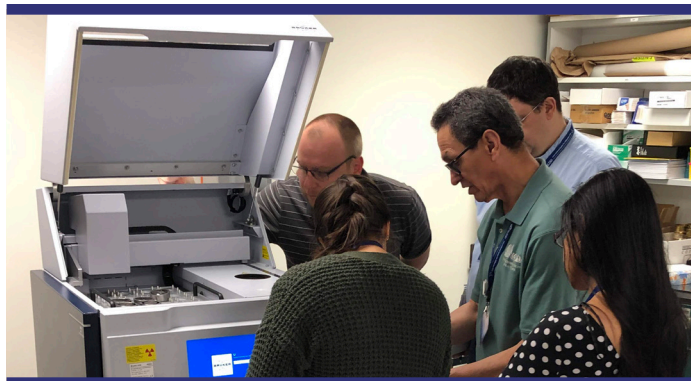
- Fundamentals of X-ray Physics
- WDX and EDX X-ray spectrometry instrumentation
- Qualitative, semi-quantitative and standardless analysis
- Introduction to quantitative analysis
- Types and sources of error
- Precision and accuracy
- Calibration strategy
- Drift, line and interelement correction application
- Fundamental parameters
- Maintaining instrument integrity
- Specimen preparation



WORKSHOPS

- XRF instrumentation, components, scope, and comparison using live and disabled WDX and EDX instrumentation
- Selection of parameters for operation
- Hands-on computer exercises in qualitative, semi-quantitative and standardless WDX and EDX analysis
- Hands-on computer exercises employing polynomial regression, line overlap, empirical and fundamental parameter correction during calibration
- Specimen preparation lecture and demonstration of the use of mixers, grinders, presses, fusion apparatus, etc.
- Discussion of problems encountered by participants

CUTTING-EDGE EQUIPMENT DEMONSTRATIONS



TXRF • HANDHELD XRF • FUSIONS

Please note: A minimum of 10 registrants per course is required, otherwise the course will be cancelled and your registration fee will be refunded. You will be notified of a course cancellation no later than two weeks prior to the start of the course.

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